

Abstract of the Disclosure:

An electromigration test structure detects the reliability of wirings. A region to be tested has an electromigration region and an electromigration barrier region formed between first 5 and second test structure terminal regions. In order to estimate a service life in a manner that is highly accurate and suitable for highly accelerated tests, a first and third sensor terminal are situated in direct proximity to the electromigration barrier region, and a second sensor terminal 10 is situated at the second test structure terminal region.

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